Koneru Lakshmaiah Education Foundation



(Deemed to be University estd. u/s. 3 of the UGC Act, 1956)

Accredited by NAAC as 'A++' Grade University *Approved by AICTE * ISO 9001-2015 Certified Campus: Green Fields, Vaddeswaram - 522 502, Guntur District, Andhra Pradesh, INDIA.

Phone No. 0863 - 2399999; www.klef.ac.in; www.klef.edu.in; www.kluniversity.in

Admin Off: 29-36-38, Museum Road, Governorpet, Vijayawada - 520 002. Ph: +91 - 866 -2577715, Fax: +91-866-2577717.

SYLLABUS FOR M.TECH (ECE) ENTRANCE EXAMINATION

I. ENGINEERING MATHEMATICS

Linear Algebra: Vector space, basis, linear dependence and independence, matrix algebra, eigenvalues and Eigenvectors, rank, solution of linear equations – existence and uniqueness. **Calculus:** Mean value theorems, theorems of integral calculus, evaluation of definite and improper integrals, partial derivatives, maxima and minima, multiple integrals, line, surface and volume integrals, Taylor series.

Differential Equations: First order equations (linear and nonlinear), higher-order linear differential equations, Cauchy's and Euler's equations, methods of solution using a variation of parameters, complementary function and particular integral, partial differential equations, variable separable method, initial and boundary value problems.

Vector Analysis: Vectors in plane and space, vector operations, gradient, divergence and curl, Gauss's, Green's and Stoke's theorems.

Complex Analysis: Analytic functions, Cauchy's integral theorem, Cauchy's integral formula; Taylor's and Laurent's series, residue theorem.

Numerical Methods: Solution of nonlinear equations, single and multi-step methods for differential equations, convergence criteria.

Probability and Statistics: Mean, median, mode and standard deviation; combinatorial probability, probability distribution functions - binomial, Poisson, exponential and normal; Joint and conditional probability; Correlation and regression analysis.

II. NETWORKS, SIGNALS AND SYSTEMS

Network solution methods: Nodal and mesh analysis; Network theorems: superposition, Thevenin and Norton's, maximum power transfer; Wye-Delta transformation; Steady state sinusoidal analysis using phasors; Time-domain analysis of simple linear circuits; Solution of network equations using Laplace transform; Frequency domain analysis of RLC circuits; Linear 2-port network parameters: driving point and transfer functions; State equations for networks.

Continuous-time signals: Fourier series and Fourier transform representations, sampling theorem and applications; Discrete-time signals: discrete-time Fourier transform (DTFT), DFT, FFT, Z-transform, interpolation of discrete-time signals; LTI systems: definition and properties, causality, stability, impulse response, convolution, poles and zeros, parallel and cascade structure, frequency response, group delay, phase delay, digital filter design techniques.

III. ELECTRONIC DEVICES

Energy bands in intrinsic and extrinsic silicon; Carrier transport: diffusion current, drift current, mobility and resistivity; Generation and recombination of carriers; Poisson and continuity equations; P-N junction, Zener diode, BJT, MOS capacitor, MOSFET, LED,

photodiode and solar cell; Integrated circuit fabrication process: oxidation, diffusion, ion implantation, photolithography and twin-tub CMOS process.

IV. ANALOG CIRCUITS

Small signal equivalent circuits of diodes, BJTs and MOSFETs; Simple diode circuits: clipping, clamping and rectifiers; Single-stage BJT and MOSFET amplifiers: biasing, bias stability, midfrequency small-signal analysis and frequency response; BJT and MOSFET amplifiers: multistage, differential, feedback, power and operational; Simple op-amp circuits; Active filters; Sinusoidal oscillators: criterion for oscillation, single-transistor and op-amp configurations; Function generators, wave-shaping circuits and 555 timers; Voltage reference circuits; Power supplies: ripple removal and regulation.

V. DIGITAL CIRCUITS

Number systems; Combinatorial circuits: Boolean algebra, minimization of functions using Boolean identities and Karnaugh map, logic gates and their static CMOS implementations, arithmetic circuits, code converters, multiplexers, decoders and PLAs; Sequential circuits: latches and flip-flops, counters, shift-registers and finite state machines; Data converters: sample and hold circuits, ADCs and DACs; Semiconductor memories: ROM, SRAM, DRAM; 8-bit microprocessor (8085): architecture, programming, memory and I/O interfacing.

VI. CONTROL SYSTEMS

Basic control system components; Feedback principle; Transfer function; Block diagram representation; Signal flow graph; Transient and steady-state analysis of LTI systems; Frequency response; Routh-Hurwitz and Nyquist stability criteria; Bode and root-locus plots; Lag, lead and lag-lead compensation; State variable model and solution of state equation of LTI systems.

VII. COMMUNICATIONS

Random processes: autocorrelation and power spectral density, properties of white noise, filtering of random signals through LTI systems; Analog communications: amplitude modulation and demodulation, angle modulation and demodulation, spectra of AM and FM, super heterodyne receivers, circuits for analogue communications; Information theory: entropy, mutual information and channel capacity theorem.

Digital communications: PCM, DPCM, digital modulation schemes, amplitude, phase and frequency shift keying (ASK, PSK, FSK), QAM, MAP and ML decoding, matched filter receiver, calculation of bandwidth, SNR and BER for digital modulation; Fundamentals of error correction, Hamming codes; Timing and frequency synchronization, inter-symbol interference and its mitigation; Basics of TDMA, FDMA and CDMA.

VIII. ELECTROMAGNETICS

Electrostatics; Maxwell's equations: differential and integral forms and their interpretation, boundary conditions, wave equation, Poynting vector; Plane waves and properties: reflection and refraction, polarization, phase and group velocity, propagation through various media, skin depth;

Transmission lines: equations, characteristic impedance, impedance matching, impedance transformation, S-parameters, Smith chart

Waveguides: modes, boundary conditions, cut-off frequencies, dispersion relations; Antennas: antenna types, radiation pattern, gain and directivity, return loss, antenna arrays; Basics of radar; Light propagation in optical fibers.

Exam Pattern – Multiple Choice Questions

Sl. No.	Subjects	No. of Questions	Marks
1	Engineering Mathematics	12	12
2	Networks, Signals and Systems	14	14
3	Electronics Devices	14	14
4	Analog Circuits	14	14
5	Digital Circuits	14	14
6	Control systems	14	14
7	Communications	14	14
8	Electromagnetics	12	12
	Total	108	108

Duration: 180 Minutes